







LMK1C1106, LMK1C1108 SNAS814A - DECEMBER 2020 - REVISED JANUARY 2022

# LMK1C110x 1.8-V, 2.5-V, and 3.3-V LVCMOS Clock Buffer Family

#### 1 Features

- High-performance 1:6 and 1:8 LVCMOS clock
- Very low output skew < 55 ps
- Extremely low additive jitter < 25-fs nominal
  - 12-fs typical at  $V_{DD} = 3.3 \text{ V}$
  - 15-fs typical at  $V_{DD} = 2.5 \text{ V}$
  - 28-fs typical at  $V_{DD}$  = 1.8 V
- Very low propagation delay < 3 ns
- Synchronous output enable
- Supply voltage: 3.3 V, 2.5 V, or 1.8 V
  - 3.3-V tolerant input at all supply voltages
  - Fail-safe inputs
- Industry high ESD rating of 9000 V HBM
- $f_{max}$  = 250 MHz for 3.3 V  $f_{max}$  = 200-MHz for 2.5 V and 1.8 V
- Operating temperature range: -40°C to 125°C
- Available in 14-pin and 16-pin TSSOP package

## 2 Applications

- Factory automation & control
- Telecommunications equipment
- Data center & enterprise computing
- Grid infrastructure
- Motor drives
- Medical imaging

## 3 Description

The LMK1C110x is a modular, high-performance, low-skew, general-purpose clock buffer family from Texas Instruments. The entire family is designed with a modular approach in mind. Five different fan-out variations, 1:2, 1:3, 1:4, 1:6 and 1:8 are available.

All of the devices within this family are pin-compatible to each other and backwards compatible to the CDCLVC110x family for easy handling.

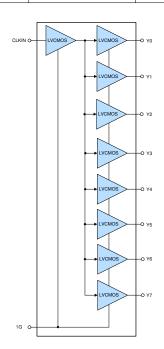
All family members share the same high performing characteristics such as low additive jitter, low skew, and wide operating temperature range.

The LMK1C110x supports a synchronous output enable control (1G) which switches the outputs into a low state when 1G is low. These devices have a fail-safe input that prevents oscillation at the outputs in the absence of an input signal and allows for input signals before VDD is supplied.

The LMK1C110x family operates in a 1.8-V, 2.5-V and 3.3-V environment and are characterized for operation from -40°C to 125°C.

### **Device Information**

| PART NUMBER | PACKAGE    | BODY SIZE (NOM)   |
|-------------|------------|-------------------|
| LMK1C1106   | TSSOP (14) | 5.00 mm x 4.40 mm |
| LMK1C1108   | TSSOP (16) | 5.00 mm x 4.40 mm |



**Functional Block Diagram** 



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# **4 Revision History**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

| Cr | hanges from Revision * (December 2020) to Revision A (January 2022) | Page |
|----|---|------|
| •  | Added fail-safe input details to Description section                | 1    |
| •  | Changed the key graphic on the first page                           | 1    |
|    | Changed part-to-part skew maximum from 950 ps to 280 ps             |      |
|    | Added the Fail-Safe Inputs section                                  |      |



# **5 Pin Configuration and Functions**

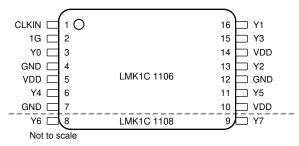


Figure 5-1. LMK1C1106 and LMK1C1108 PW Package 14-Pin TSSOP and 16-Pin TSSOP Top View

**Table 5-1. Pin Functions** 

|          | PIN           |               |        |   |
|----------|---------------|---------------|--------|---|
| NAME     | LMK1C<br>1106 | LMK1C<br>1108 | TYPE   | DESCRIPTION   |
| LVCMOS C | LOCK INPUT    |               |        |   |
| CLKIN    | 1             | 1             | Input  | Single-ended clock input with internal 300-k $\Omega$ (typical) pulldown resistor to GND. Typically connected to a single-ended clock input.  |
| CLOCK OL | JTPUT ENABLE  |               | •      |   |
| 1G       | 2             | 2             | Input  | Global Output Enable with internal 300-k $\Omega$ (typical) pulldown resistor to GND. Typically connected to VDD with external pullup resistor. HIGH: outputs enabled LOW: outputs disabled |
| LVCMOS C | LOCK OUTPUT   |               | •      |   |
| Y0       | 3             | 3             |        |   |
| Y1       | 14            | 16            |        |   |
| Y2       | 11            | 13            |        |   |
| Y3       | 13            | 15            | 0      | LVCMOS output. Typically connected to a receiver. Unused outputs can be   |
| Y4       | 6             | 6             | Output | left floating.  |
| Y5       | 9             | 11            |        |   |
| Y6       | _             | 8             |        |   |
| Y7       | _             | 9             |        |   |
| SUPPLY V | OLTAGE        |               | •      |   |
|          | 5             | 5             |        | Power supply terminal. Typically connected to a 3.3-V, 2.5-V, or 1.8-V supply.  |
| VDD      | 8             | 10            | Power  | The VDD pin is typically connected to an external 0.1-µF capacitor near the   |
|          | 12            | 14            |        | pin.  |
| GROUND   |               |               | •      |   |
|          | 4             | 4             |        |   |
| GND      | 7             | 7             | GND    | Device ground.  |
|          | 10            | 12            |        |   |



## **6 Specifications**

## **6.1 Absolute Maximum Ratings**

over operating free-air temperature range (unless otherwise noted)(1)

|                    |                           | MIN  | MAX                   | UNIT |
|--------------------|---------------------------|------|-----------------------|------|
| $V_{DD}$           | Supply voltage            |      |                       |      |
| V <sub>CLKIN</sub> | Input voltage (CLKIN)     | -0.5 | 3.6                   | V    |
| V <sub>IN</sub>    | Input voltage (1G)        |      |                       | V    |
| V <sub>Yn</sub>    | Output pins (Yn)          | -0.5 | V <sub>DD</sub> + 0.3 |      |
| I <sub>IN</sub>    | Input current             | -20  | 20                    | mA   |
| I <sub>O</sub>     | Continuous output current | -50  | 50                    | mA   |
| T <sub>stg</sub>   | Storage temperature       | -65  | 150                   | °C   |

<sup>(1)</sup> Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

## 6.2 ESD Ratings

|        |                         |  | VALUE | UNIT |
|--------|-------------------------|--|-------|------|
| V      | Floatrostatio discharge | Human body model (HBM), per ANSI/ESDA/<br>JEDEC JS-001, all pins <sup>(1)</sup>          | ±9000 | \/   |
| V(ESD) | Electrostatic discharge | Charged device model (CDM), per JEDEC specification JESD22-C101, all pins <sup>(2)</sup> | ±1500 | V    |

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

### 6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

|                |                                |              |     | MIN   | NOM | MAX   | UNIT |
|----------------|--------------------------------|--------------|-----|-------|-----|-------|------|
|                |                                | 3.3-V supply |     | 3.135 | 3.3 | 3.465 |      |
| $V_{DD}$       | Core supply voltage            | 2.5-V supply |     | 2.375 | 2.5 | 2.625 | V    |
|                |                                | 1.8-V supply |     | 1.71  | 1.8 | 1.89  |      |
| T <sub>A</sub> | Operating free-air temperature |              |     | -40   |     | 125   | °C   |
| TJ             | Operating junction temperature |              | -40 |       | 150 | °C    |      |

### 6.4 Thermal Information

|                               |  | LMK1C1106  | LMK1C1108 |      |
|-------------------------------|--|------------|-----------|------|
| THERMAL METRIC <sup>(1)</sup> |  | PW (TSSOP) | PW(TSSOP) | UNIT |
|                               |  | 14 PINS    | 16 PINS   |      |
| R <sub>qJA</sub>              | Junction-to-ambient thermal resistance       | 114.4      | 123.4     | °C/W |
| R <sub>qJC(top)</sub>         | Junction-to-case (top) thermal resistance    | 45.2       | 53.1      | °C/W |
| R <sub>qJB</sub>              | Junction-to-board thermal resistance         | 60.6       | 66.4      | °C/W |
| $Y_{JT}$                      | Junction-to-top characterization parameter   | 5.9        | 8.9       | °C/W |
| $Y_{JB}$                      | Junction-to-board characterization parameter | 60         | 65.8      | °C/W |

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



## **6.5 Electrical Characteristics**

VDD = 3.3 V ± 5 %, -40°C ≤ TA ≤ 125°C. Typical values are at VDD = 3.3 V, 25°C (unless otherwise noted)

|                         | PARAMETER                             | TEST CONDITIONS  | MIN                   | TYP  | MAX                  | UNIT    |
|-------------------------|---------------------------------------|--|-----------------------|------|----------------------|---------|
| CURRENT                 | CONSUMPTION                           |  |                       |      |                      |         |
| I <sub>DD</sub>         | Core supply current, static           | All-outputs disabled, f <sub>IN</sub> = 0 V  |                       | 25   | 45                   | μA      |
| I <sub>DD</sub>         | Core supply current                   | All-outputs disabled, $f_{IN}$ = 100 MHz, $V_{DD}$ = 1.8 V                                       |                       | 2    | 6                    | mA      |
| I <sub>DD</sub>         | Core supply current                   | All-outputs disabled, $f_{IN}$ = 100 MHz, $V_{DD}$ = 2.5 V                                       |                       | 6.5  | 10                   | mA      |
| I <sub>DD</sub>         | Core supply current                   | All-outputs disabled, f <sub>IN</sub> = 100 MHz, V <sub>DD</sub> = 3.3 V                         |                       | 15   | 21                   |         |
|                         |                                       | Per output, f <sub>IN</sub> = 100 MHz, C <sub>L</sub> = 5pF, V <sub>DD</sub> = 1.8 V             |                       | 3.2  | 3.5                  |         |
| I <sub>DD</sub>         | Output current                        | Per output, $f_{IN}$ = 100 MHz, $C_L$ = 5pF, $V_{DD}$ = 2.5 V                                    |                       | 4.6  | 5.5                  | mA      |
|                         |                                       | Per output, $f_{IN}$ = 100 MHz, $C_L$ = 5pF, $V_{DD}$ = 3.3 V                                    |                       | 6    | 7                    |         |
| CLOCK INF               | TUY                                   |  |                       |      |                      |         |
|                         | I                                     | V <sub>DD</sub> = 3.3 V  | DC                    |      | 250                  | MU      |
| f <sub>IN_SE</sub>      | Input frequency                       | V <sub>DD</sub> = 2.5 V and 1.8 V  | DC                    |      | 200                  | MHz     |
| V <sub>IH</sub>         | Input high voltage                    |  | 0.7 x V <sub>DD</sub> |      |                      | .,      |
| V <sub>IL</sub>         | Input low voltage                     |  |                       | 0.   | .3 x V <sub>DD</sub> | V       |
| dV <sub>IN</sub> /dt    | Input slew rate                       | 20% - 80% of input swing   | 0.1                   |      |                      | V/ns    |
| I <sub>IN_LEAK</sub>    | Input leakage current                 |  | -50                   |      | 50                   | uA      |
| C <sub>IN_SE</sub>      | Input capacitance                     | at 25°C  |                       | 7    |                      | pF      |
|                         | TPUT FOR ALL V <sub>DD</sub> LEVELS   |  |                       |      |                      | •       |
|                         |                                       | V <sub>DD</sub> = 3.3 V  |                       |      | 250                  |         |
| f <sub>OUT</sub>        | Output frequency                      | V <sub>DD</sub> = 2.5 V and 1.8 V  |                       |      | 200                  | MHz     |
| ODC                     | Output duty cycle                     | With 50% duty cycle input  | 45                    |      | 55                   | %       |
| t <sub>1G_ON</sub>      | Output enable time                    | See <sup>(1)</sup>   |                       |      | 5                    | cycles  |
| t <sub>1G OFF</sub>     | Output disable time                   | See <sup>(2)</sup>   |                       |      | 5                    | cycles  |
|                         | TPUT FOR V <sub>DD</sub> = 3.3 V ± 5% |  |                       |      |                      | ,       |
| V <sub>OH</sub>         | Output high voltage                   | I <sub>OH</sub> = 1 mA   | 2.8                   |      |                      |         |
| V <sub>OL</sub>         | Output low voltage                    | I <sub>OL</sub> = 1 mA   |                       |      | 0.2                  | V       |
| t <sub>RISE-FALL</sub>  | Output rise and fall time             | 20/80%, C <sub>L</sub> = 5 pF, fIN = 156.25 MHz  |                       | 0.3  | 0.7                  | ns      |
| t <sub>OUTPUT</sub> -   | Output-output skew                    | See <sup>(3)</sup>   |                       | 35   | 55                   | ps      |
| t <sub>PART-SKEW</sub>  | Part-to-part skew                     |  |                       |      | 280                  | ро      |
| t <sub>PROP-DELAY</sub> | Propagation delay                     | See <sup>(4)</sup>   |                       | 1.3  | 2.2                  | ns      |
| t <sub>JITTER-ADD</sub> | Additive Jitter                       | f <sub>IN</sub> = 156.25 MHz, Input slew rate = 1.6<br>V/ns, Integration range = 12 kHz - 20 MHz |                       | 12   | 20                   | fs, RMS |
| R <sub>OUT</sub>        | Output impedance                      |  |                       | 50   |                      | Ω       |
|                         | TPUT FOR V <sub>DD</sub> = 2.5 V ± 5% |  | 1                     |      |                      |         |
| V <sub>OH</sub>         | Output high voltage                   | I <sub>OH</sub> = 1 mA   | 0.8 x V <sub>DD</sub> |      |                      |         |
| V <sub>OL</sub>         | Output low voltage                    | I <sub>OL</sub> = 1 mA   | ,,,,,,,               | 0    | 2 x V <sub>DD</sub>  | V       |
| t <sub>RISE-FALL</sub>  | Output rise and fall time             | 20/80%, C <sub>L</sub> = 5 pF, f <sub>IN</sub> = 156.25 MHz                                      |                       | 0.33 | 0.8                  | ns      |
| t <sub>OUTPUT</sub> -   | Output-output skew                    | See (3)  |                       |      | 55                   |         |
| t <sub>PART-SKEW</sub>  | Part-to-part skew                     |  |                       |      | 450                  | ps      |
| t <sub>PROP-DELAY</sub> | Propagation delay                     | See <sup>(4)</sup>   | +                     | 1.5  | 2.5                  | ns      |



VDD =  $3.3 \text{ V} \pm 5 \text{ %}$ ,  $-40 ^{\circ}\text{C} \leq \text{TA} \leq 125 ^{\circ}\text{C}$ . Typical values are at VDD = 3.3 V,  $25 ^{\circ}\text{C}$  (unless otherwise noted)

|                         | PARAMETER                             | TEST CONDITIONS  | MIN                       | TYP  | MAX                       | UNIT    |
|-------------------------|---------------------------------------|--|---------------------------|------|---------------------------|---------|
| t <sub>JITTER-ADD</sub> | Additive Jitter                       | f <sub>IN</sub> = 156.25 MHz, Input slew rate = 1.2<br>V/ns, Integration range = 12 kHz - 20 MHz |                           | 15   | 27                        | fs, RMS |
| R <sub>OUT</sub>        | Output impedance                      |  |                           | 55   |                           | Ω       |
| CLOCK OU                | TPUT FOR V <sub>DD</sub> = 1.8 V ± 5% |  |                           |      |                           |         |
| V <sub>OH</sub>         | Output high voltage                   | I <sub>OH</sub> = 1 mA   | 0.8 x V <sub>DD</sub>     |      |                           | V       |
| V <sub>OL</sub>         | Output low voltage                    | I <sub>OL</sub> = 1 mA   |                           | (    | 0.2 x V <sub>DD</sub>     | V       |
| t <sub>RISE-FALL</sub>  | Output rise and fall time             | 20/80%, C <sub>L</sub> = 5 pF, f <sub>IN</sub> = 156.25 MHz                                      |                           | 0.38 | 1                         | ns      |
| t <sub>OUTPUT</sub> -   | Output-output skew                    | See (3)  |                           |      | 55                        | ps      |
| t <sub>PART-SKEW</sub>  | Part-to-part skew                     |  |                           |      | 930                       | ps      |
| t <sub>PROP-DELAY</sub> | Propagation delay                     | See <sup>(4)</sup>   |                           | 1.5  | 3                         | ns      |
| t <sub>JITTER-ADD</sub> | Additive Jitter                       | f <sub>IN</sub> = 156.25 MHz, Input slew rate = 1.2 V/ns, Integration range = 12 kHz - 20 MHz    |                           | 28   | 60                        | fs, RMS |
| R <sub>OUT</sub>        | Output impedance                      |  |                           | 64   |                           | Ω       |
| GENERAL I               | PURPOSE INPUT (1G)                    |  |                           |      |                           |         |
| V <sub>IH</sub>         | High-level input voltage              |  | 0.75 x<br>V <sub>DD</sub> |      |                           | V       |
| V <sub>IL</sub>         | Low-level input voltage               |  |                           |      | 0.25 x<br>V <sub>DD</sub> | V       |
| I <sub>IH</sub>         | Input high-level current              | $V_{IH} = V_{DD\_REF}$   | -50                       |      | 50                        |         |
| I <sub>IL</sub>         | Input low-level current               | V <sub>IL</sub> = GND  | -50                       |      | 50                        | μA      |

- (1)
- Measured from 1G rising edge crossing VIH to first rising edge of Yn. Measured from 1G falling edge crossing VIL to last falling edge of Yn. (2)
- Measured from rising edge of any Yn output to any other Ym output. Measured from rising edge of CLKIN to any Yn output. (3)

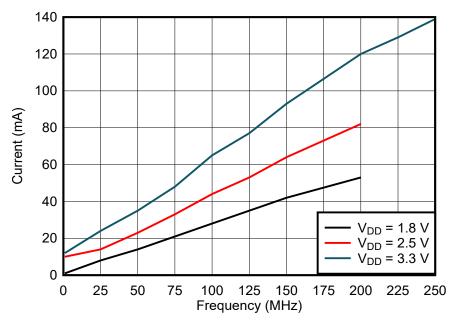
## **6.6 Timing Requirements**

 $VDD = 3.3 V \pm 5 \%, -40^{\circ}C \le TA \le 125^{\circ}C$ 

|                     |                           |  | MIN | NOM | MAX | UNIT |  |
|---------------------|---------------------------|--|-----|-----|-----|------|--|
| POWER S             | POWER SUPPLY              |  |     |     |     |      |  |
| V/t <sub>RAMP</sub> | V <sub>DD</sub> ramp rate |  | 0.1 |     | 50  | V/ms |  |



# **6.7 Typical Characteristics**



Device Power Consumption vs. Clock Frequency (Load 5 pF)



## 7 Parameter Measurement Information

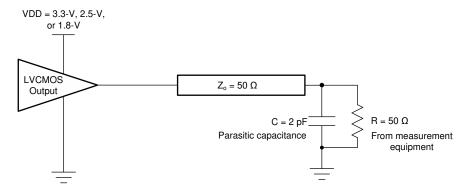


Figure 7-1. Test Load Circuit

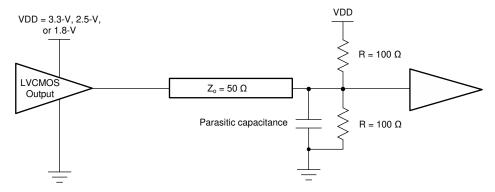


Figure 7-2. Application Load With 50-Ω Termination

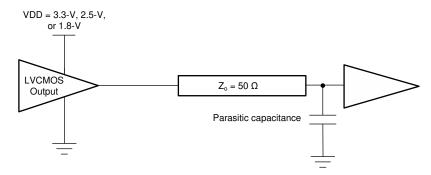


Figure 7-3. Application Load With Termination

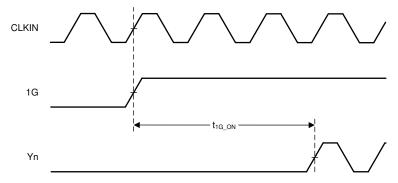


Figure 7-4.  $t_{1G\ ON}$  Output Enable Time

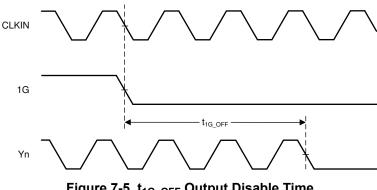


Figure 7-5.  $t_{1G\_OFF}$  Output Disable Time

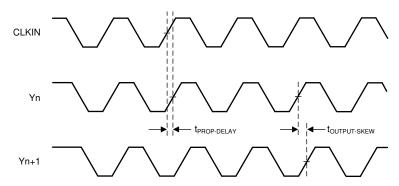


Figure 7-6. Propagation Delay  $t_{\mbox{\scriptsize PROP-DELAY}}$  and Output Skew  $t_{\mbox{\scriptsize OUTPUT-SKEW}}$ 



Figure 7-7. Rise and Fall Time  $t_{\mbox{\scriptsize RISE-FALL}}$ 

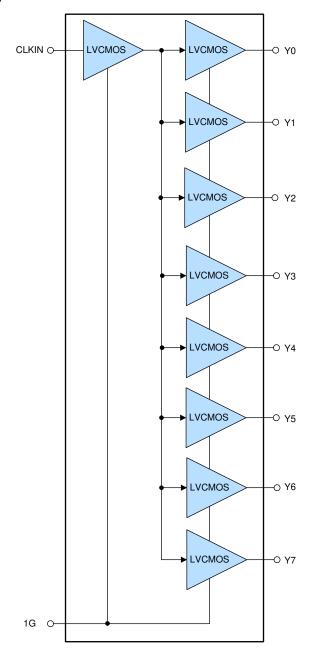


## **8 Detailed Description**

## 8.1 Overview

The LMK1C110x family of devices is part of a low-jitter and low-skew LVCMOS fan-out buffer solution. For best signal integrity, it is important to match the characteristic impedance of the LMK1C110x's output driver with that of the transmission line.

## 8.2 Functional Block Diagram



### 8.3 Feature Description

The outputs of the LMK1C110x can be disabled by driving the synchronous output enable pin (1G) low. Unused output can be left floating to reduce overall system component cost. Supply and ground pins must be connected to  $V_{DD}$  and GND, respectively.

### 8.3.1 Fail-Safe Inputs

The LMK1C110x family of devices is designed to support fail-safe input operation. This feature allows the user to drive the device inputs before VDD is applied without damaging the device. Refer to *Absolute Maximum Ratings* for more information on the maximum input supported by the device. The device also incorporates an input hysteresis that prevents random oscillation in absence of an input signal, allowing the input pins to be left open.

### 8.4 Device Functional Modes

The LMK1C110x operates from 1.8-V, 2.5-V, or 3.3-V supplies. Table 8-1 shows the output logics of the LMK1C110x.

Table 8-1. Output Logic Table

| INP   | OUTPUTS |    |
|-------|---------|----|
| CLKIN | 1G      | Yn |
| X     | L       | L  |
| L     | Н       | L  |
| Н     | Н       | Н  |

## 9 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

### 9.1 Application Information

The LMK1C110x family is a low additive jitter LVCMOS buffer solution that can operate up to 250-MHz at  $V_{DD}$  = 3.3 V and 200 MHz at  $V_{DD}$  = 2.5 V to 1.8 V. Low output skew as well as the ability for synchronous output enable is featured to simultaneously enable or disable buffered clock outputs as necessary in the application.

### 9.2 Typical Application

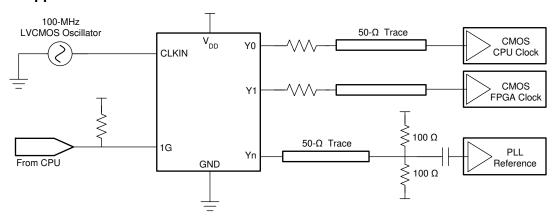


Figure 9-1. System Configuration Example

#### 9.2.1 Design Requirements

The LMK1C110x shown in Figure 9-1 is configured to fan out a 100-MHz signal from a local LVCMOS oscillator. The CPU is configured to control the output state through 1G.

The configuration example is driving three LVCMOS receivers in a backplane application with the following properties:

- The CPU clock can accept a full swing DC-coupled LVCMOS signal. A series resistor is placed near the LMK1C110x to closely match the characteristic impedance of the trace to minimize reflections.
- The FPGA clock is similarly DC-coupled with an appropriate series resistor placed near the LMK1C110x.
- The PLL in this example can accept a lower amplitude signal, so a Thevenin's equivalent termination is used.
   The PLL receiver features internal biasing, so AC coupling can be used when common-mode voltage is mismatched.

#### 9.2.2 Detailed Design Procedure

Unused outputs can be left floating. See *Power Supply Recommendations* for recommended filtering techniques.

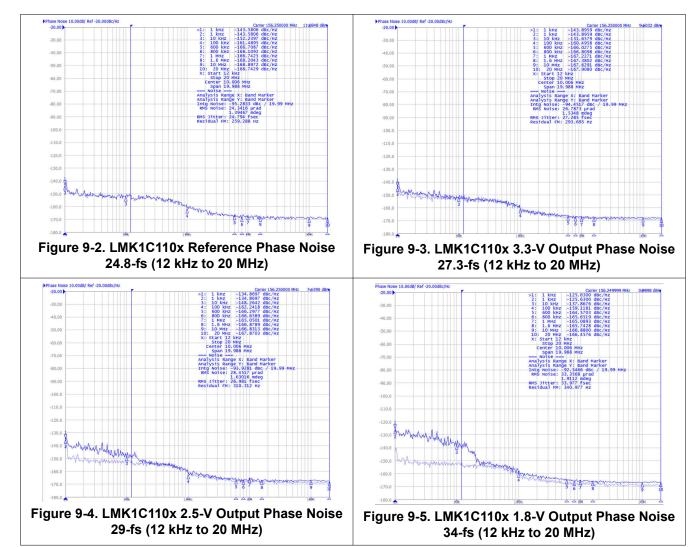
#### 9.2.3 Application Curves

The low additive jitter of the LMK1C110x is shown in Figure 9-2.

Figure 9-3 shows the low-noise 156.25-MHz reference source with 24.8-fs RMS jitter driving the LMK1C110x, resulting in 27.3-fs RMS jitter when integrated from 12 kHz to 20 MHz at 3.3-V supply. The resultant additive jitter measured is a low 11.4-fs RMS for this configuration.

Figure 9-4 shows the low-noise 156.25-MHz reference source with 24.8-fs RMS jitter driving the LMK1C110x, resulting in 29-fs RMS jitter when integrated from 12 kHz to 20 MHz at 2.5-V supply. The resultant additive jitter measured is a low 15-fs RMS for this configuration.

Figure 9-5 shows the low-noise 156.25-MHz reference source with 24.8-fs RMS jitter driving the LMK1C110x, resulting in 34-fs RMS jitter when integrated from 12 kHz to 20 MHz at 1.8-V supply. The resultant additive jitter measured is a low 23.25-fs RMS for this configuration.



## 10 Power Supply Recommendations

High-performance clock buffers can be sensitive to noise on the power supply, which may dramatically increase the additive jitter of the buffer. Thus, it is essential to manage any excessive noise from the system power supply, especially for applications where the jitter and phase noise performance is critical.

Filter capacitors are used to eliminate the low-frequency noise from the power supply, where the bypass capacitors provide the very low impedance path for high-frequency noise and guard the power supply system against induced fluctuations. These bypass capacitors also provide instantaneous current surges as required by the device and should have low equivalent series resistance (ESR). To properly bypass the supply, the decoupling capacitors must be placed very close to the power-supply terminals, be connected directly to the ground plane, and laid out with short loops to minimize inductance. TI recommends adding as many high-frequency (for example, 0.1 µF) bypass capacitors, as there are supply terminals in the package. TI recommends, but does not require, inserting a ferrite bead between the board power supply and the chip power supply that isolates the high-frequency switching noises generated by the clock buffer; these beads prevent the switching noise from leaking into the board supply. It is imperative to choose an appropriate ferrite bead with very low DC resistance to provide adequate isolation between the board supply and the chip supply, as well as to maintain a voltage at the supply terminals that is greater than the minimum voltage required for proper operation.

Figure 10-1 shows this recommended power supply decoupling method.

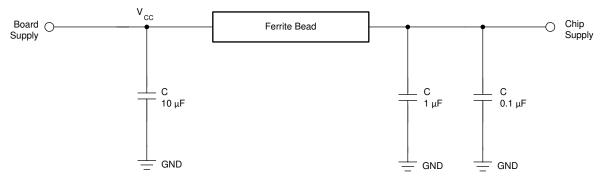


Figure 10-1. Power Supply Decoupling



## 11 Layout

## 11.1 Layout Guidelines

Figure 11-1 shows a conceptual layout detailing recommended placement of power supply bypass capacitors. For component side mounting, use 0402 body size capacitors to facilitate signal routing. Keep the connections between the bypass capacitors and the power supply on the device as short as possible. Ground the other side of the capacitor using a low-impedance connection to the ground plane.

## 11.2 Layout Example

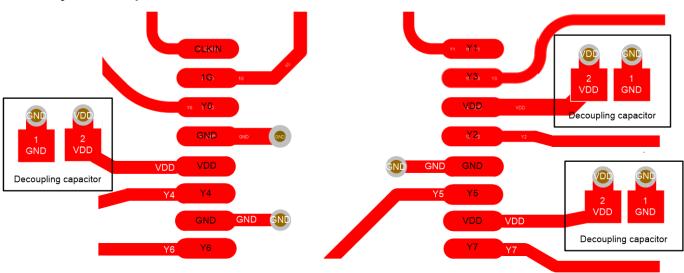


Figure 11-1. PCB Conceptual Layout

## 12 Device and Documentation Support

## **12.1 Documentation Support**

### 12.1.1 Related Documentation

For related documentation, see the following:

#### LMK1C1108EVM User Guide

### 12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

## 12.3 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 12.4 Trademarks

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### 12.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 12.6 Glossary

TI Glossarv

This glossary lists and explains terms, acronyms, and definitions.

## 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### PACKAGING INFORMATION

| Orderable part number | Status | Material type | Package   Pins  | Package qty   Carrier | RoHS | Lead finish/<br>Ball material | MSL rating/<br>Peak reflow | Op temp (°C) | Part marking (6) |
|-----------------------|--------|---------------|-----------------|-----------------------|------|-------------------------------|----------------------------|--------------|------------------|
|                       | (.,    | (=)           |                 |                       | (8)  | (4)                           | (5)                        |              | (0)              |
| LMK1C1106PWR          | Active | Production    | TSSOP (PW)   14 | 3000   LARGE T&R      | Yes  | NIPDAU   SN                   | Level-1-260C-UNLIM         | -40 to 125   | LMK1C6           |
| LMK1C1106PWR.A        | Active | Production    | TSSOP (PW)   14 | 3000   LARGE T&R      | Yes  | NIPDAU                        | Level-1-260C-UNLIM         | -40 to 125   | LMK1C6           |
| LMK1C1108PWR          | Active | Production    | TSSOP (PW)   16 | 3000   LARGE T&R      | Yes  | NIPDAU   SN                   | Level-1-260C-UNLIM         | -40 to 125   | LMK1C8           |
| LMK1C1108PWR.A        | Active | Production    | TSSOP (PW)   16 | 3000   LARGE T&R      | Yes  | NIPDAU                        | Level-1-260C-UNLIM         | -40 to 125   | LMK1C8           |
| LMK1C1108PWRG4        | Active | Production    | TSSOP (PW)   16 | 3000   LARGE T&R      | Yes  | NIPDAU                        | Level-1-260C-UNLIM         | -40 to 125   | LMK1C8           |
| LMK1C1108PWRG4.A      | Active | Production    | TSSOP (PW)   16 | 3000   LARGE T&R      | Yes  | NIPDAU                        | Level-1-260C-UNLIM         | -40 to 125   | LMK1C8           |

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



# **PACKAGE OPTION ADDENDUM**

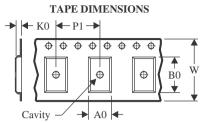
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# **PACKAGE MATERIALS INFORMATION**

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## TAPE AND REEL INFORMATION





| A0 | Dimension designed to accommodate the component width     |
|----|---|
| В0 | Dimension designed to accommodate the component length    |
| K0 | Dimension designed to accommodate the component thickness |
| W  | Overall width of the carrier tape                         |
| P1 | Pitch between successive cavity centers                   |

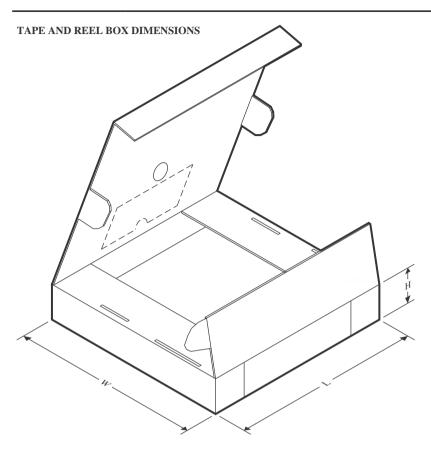
### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

| Device         | Package<br>Type | Package<br>Drawing |    | SPQ  | Reel<br>Diameter<br>(mm) | Reel<br>Width<br>W1 (mm) | A0<br>(mm) | B0<br>(mm) | K0<br>(mm) | P1<br>(mm) | W<br>(mm) | Pin1<br>Quadrant |
|----------------|-----------------|--------------------|----|------|--------------------------|--------------------------|------------|------------|------------|------------|-----------|------------------|
| LMK1C1106PWR   | TSSOP           | PW                 | 14 | 3000 | 330.0                    | 12.4                     | 6.9        | 5.6        | 1.6        | 8.0        | 12.0      | Q1               |
| LMK1C1108PWR   | TSSOP           | PW                 | 16 | 3000 | 330.0                    | 12.4                     | 6.9        | 5.6        | 1.6        | 8.0        | 12.0      | Q1               |
| LMK1C1108PWRG4 | TSSOP           | PW                 | 16 | 3000 | 330.0                    | 12.4                     | 6.9        | 5.6        | 1.6        | 8.0        | 12.0      | Q1               |

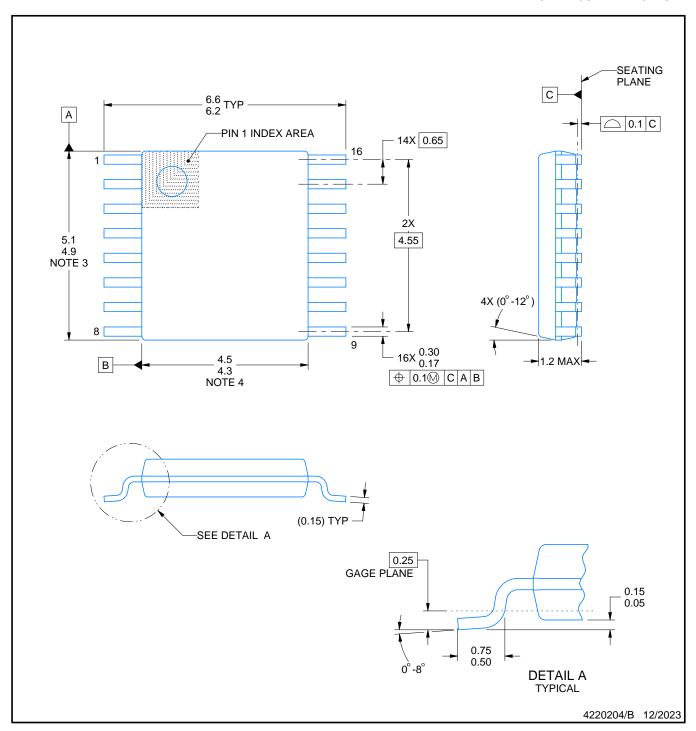
www.ti.com 2-Nov-2025



## \*All dimensions are nominal

| Device         | Package Type | Package Drawing | Pins | SPQ  | Length (mm) | Width (mm) | Height (mm) |
|----------------|--------------|-----------------|------|------|-------------|------------|-------------|
| LMK1C1106PWR   | TSSOP        | PW              | 14   | 3000 | 356.0       | 356.0      | 35.0        |
| LMK1C1108PWR   | TSSOP        | PW              | 16   | 3000 | 356.0       | 356.0      | 35.0        |
| LMK1C1108PWRG4 | TSSOP        | PW              | 16   | 3000 | 353.0       | 353.0      | 32.0        |





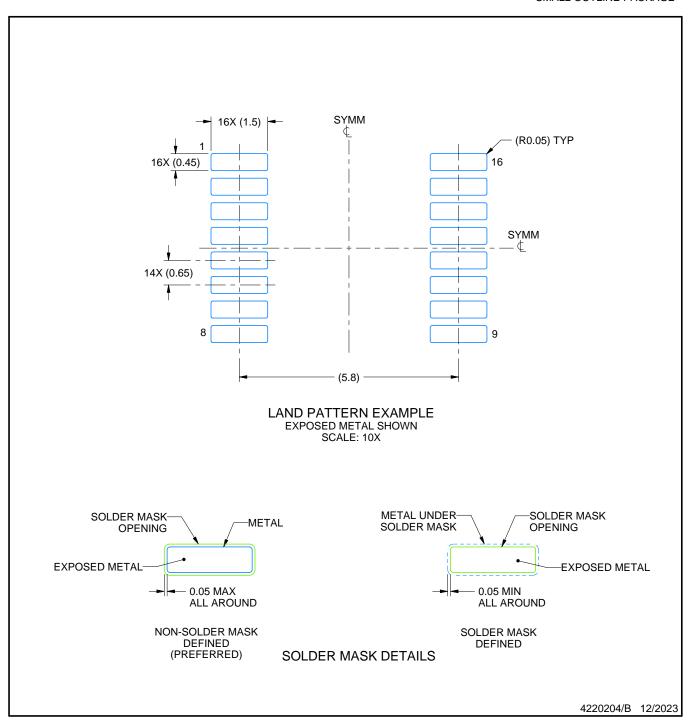
### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.

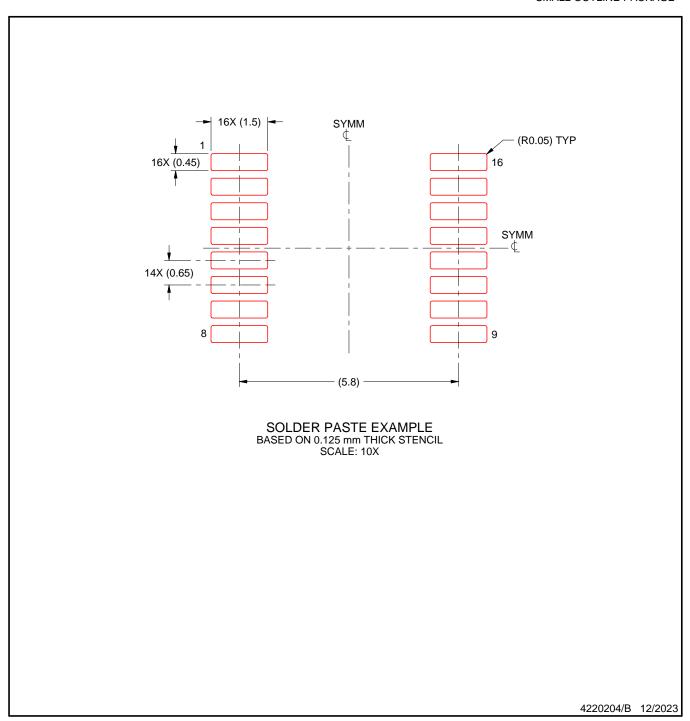




NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



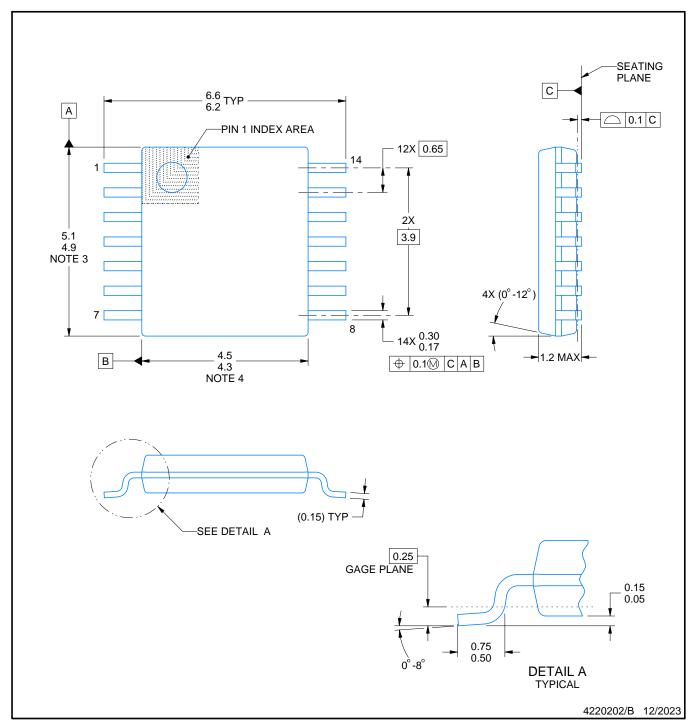


NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







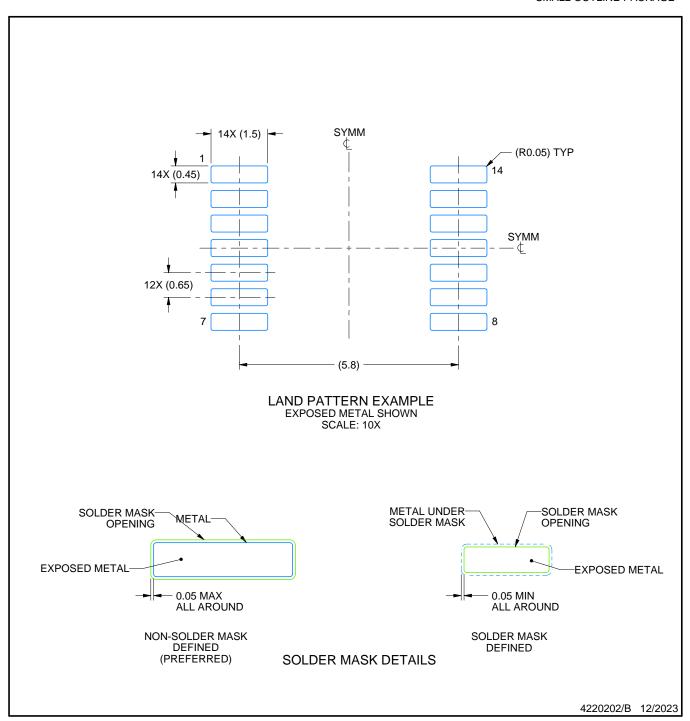
### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



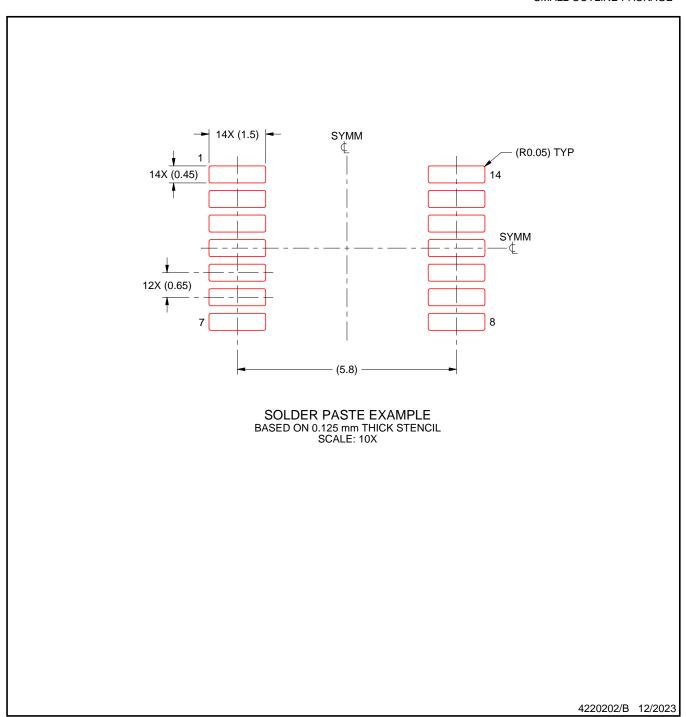


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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